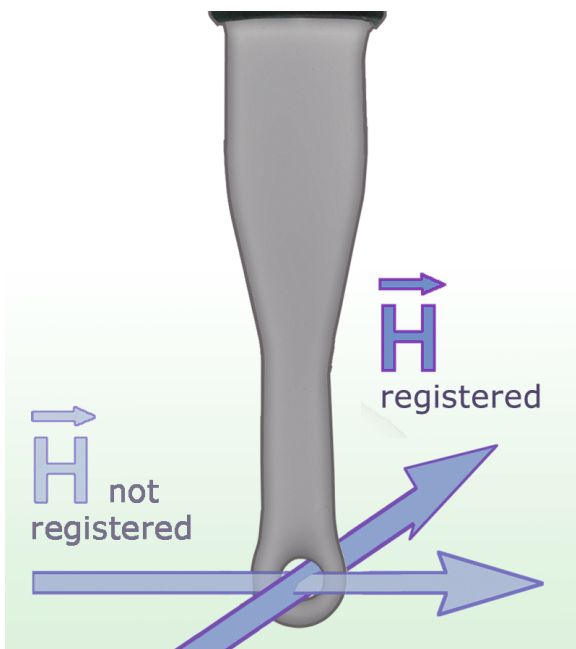


XFS-R 3-1

Scanner Probe 30 MHz up to 6 GHz



Short description

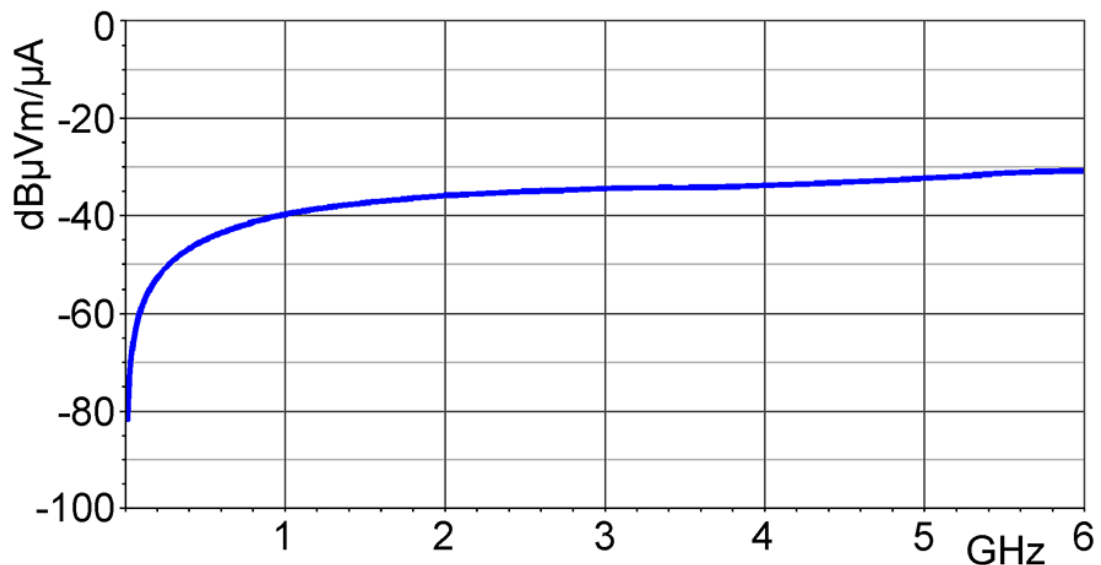
The XFS-R 3-1 scanner probe is designed for direct high-resolution measurements of RF magnetic fields on an assembly, e.g. around the pins and IC cases, conducting paths, decoupling capacitor, and EMC components.

The XFS-R 3-1 H-field scanner probe is suitable for measurements close to the components with high magnetic field strength. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	≈ 1 mm
Probe head dimensions:	$\varnothing \approx 3$ mm
Connector - output	SMA, male, jack

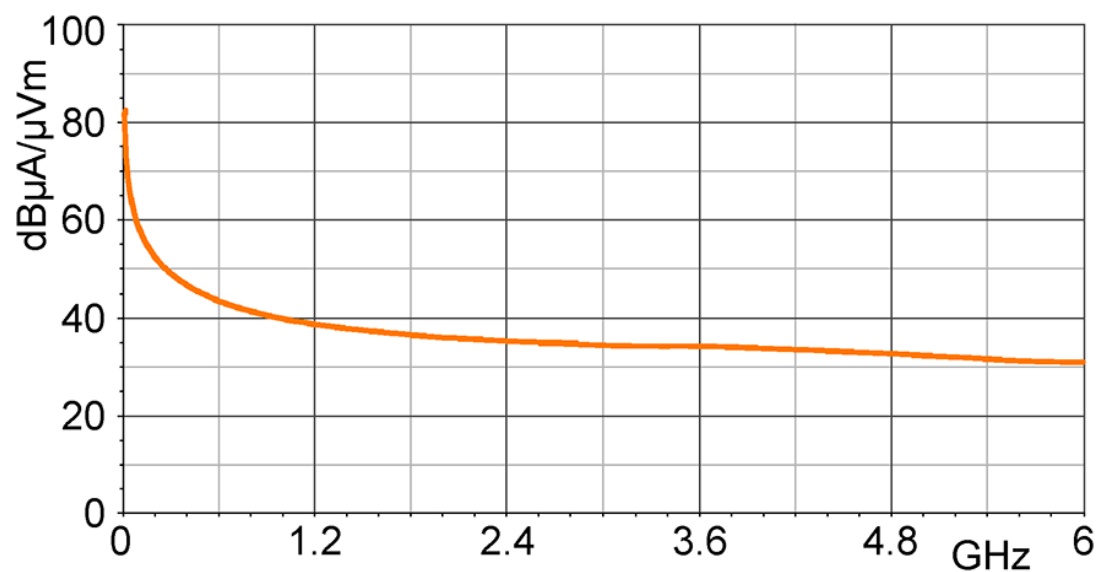
Frequency response [dB μ V] / [dB μ A/m]



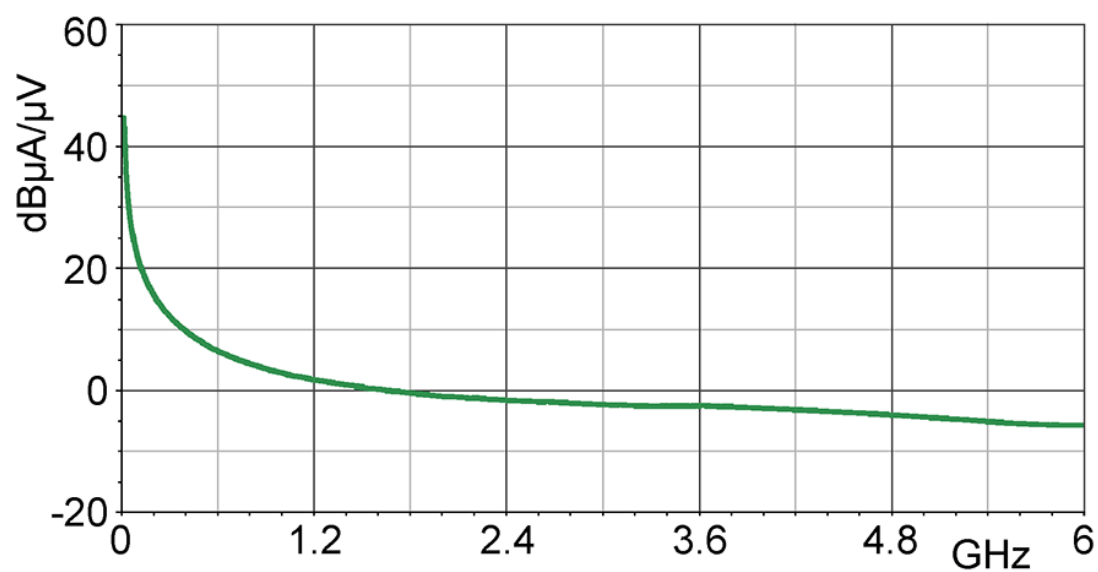
XFS-R 3-1

Scanner Probe 30 MHz up to 6 GHz

H-field correction curve [dB μ A/m] / [dB μ V]



Current correction curve [dB μ A] / [dB μ V]



XFS-R 3-1

Scanner Probe 30 MHz up to 6 GHz

LANGER
EMV-Technik

Measuring principles

